### Photocouplers GaAłAs Infrared LED & Photo IC

# TLP5214

±4.0 A (max)

3.5 mA (max)

15 V to 30 V

150 ns (max)

±35 kV/μs (min) 5000 Vrms (min)

-40°C to 110°C

 $I_{FLH} = 6 \text{ mA} (\text{max})$ 

### Isolated IGBT/Power MOSFET gate drive AC and brushless DC motor drives Industrial Inverters and Uninterruptible Power Supply (UPS)

The TLP5214 is a highly integrated 4.0A output current IGBT gate drive photocoupler housed in a long creepage and clearance SO16L package.

The TLP5214, a smart gate driver photocoupler, includes functions of IGBT desaturation detection, isolated fault status feedback, soft IGBT turn-off, active Miller cramping and under voltage lockout (UVLO).

This photocoupler is suitable for driving IGBT and power MOSFET used in inverter applications.

The TLP5214 consists two GaAlAs infrared light-emitting diodes (LEDs) and two high-gain and high-speed ICs. They realize high current, high-speed output control and output fault status feedback.

- Peak output current:
- Guaranteed performance over temperature:
- Supply current:
- Power supply voltage:
- Threshold input current:
- Switching time (tpLH / tpHL) :
- Common mode transient immunity:
- Isolation voltage:
- UL approved : UL1577, File No.E67349
- c-UL approved :CSA Component Acceptance Service No. 5A, File No.E67349
- Option (D4) VDE approved : DIN EN60747-5-5(Note)

EN60065 or EN60950-1,

EN62368-1 (Pending)

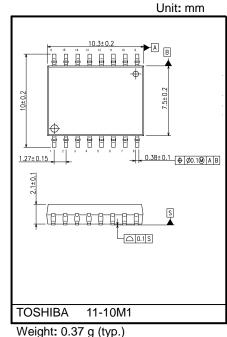
CQC-approved: GB4943.1, GB8898 Japan Factory

#### Note : When a EN60747-5-5 approved type is needed, please designate "Option(D4)"

### **Truth Table**

I <sub>F</sub>	UVLO DESAT		FAULT	Vo	
	$(V_{CC2}-V_E)$	(14Pin DESAT Terminal Input)	(3Pin FAULT Terminal Output)		
OFF	Not Active ( $> V_{UVLO}^+$ )	Not Active	High	Low	
ON	Not Active ( $> V_{UVLO}^+$ )	Low ( < V <sub>DESATth</sub> )	High	High	
ON	Not Active ( $> V_{UVLO}^+$ )	High ( > $V_{DESATth}$ )	Low ( FAULT)	Low	
ON	Active ( < V <sub>UVLO</sub> <sup>-</sup> )	Not Active	High	Low	
OFF	Active ( < V <sub>UVLO</sub> <sup>-</sup> )	Not Active	High	Low	

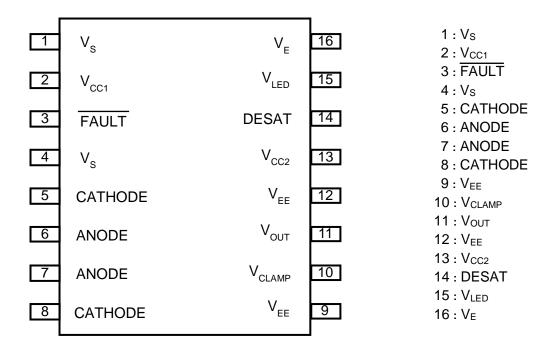
Start of commercial production 2014-05 2015-10-30



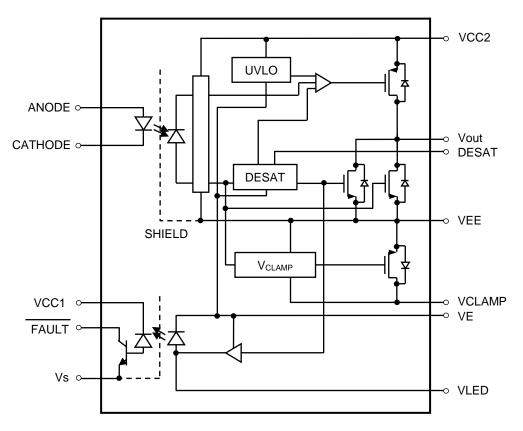
Construction mechanical rating

	SO16L
Height	2.3 mm (max)
Creepage Distance	8.0 mm (min)
Clearance	8.0 mm (min)
Insulation Thickness	0.4 mm (min)

### Pin Configuration (top view)



### **Internal Circuit**



Note: A  $1-\mu F$  bypass capacitor must be connected between pins 9 and 13, pins 13 and 16.

### Absolute Maximum Ratings (Note) (Ta = 25°C ,Unless otherwise specified)

	Characteristic	Symbol	Rating	Unit	
LED	Input forward current	lF	25	mA	
	Input forward current derating (Ta ≥	95°C)	∆l <sub>F</sub> /∆Ta	-1	mA/°C
	Peak transient input forward current	(Note 1)	IFPT	1	A
	Peak transient input forward current of	lerating (Ta ≥ 95°C)	ΔΙ <sub>ΓΡΤ</sub> /ΔΤα	-25	mA/°C
	Reverse Input Voltage		V <sub>R</sub>	6	V
	Input power dissipation		PD	40	mW
	Input power dissipation derating (Ta	≥ 95°C)	$\Delta P_D / \Delta Ta$	-1.3	mW/°C
Detector	Positive Input Supply Voltage		V <sub>CC1</sub>	-0.5 to 7	V
	"H" peak output current	Ta = -40 to 110 °C	Іорн	-4.0	А
	"L" peak output current	(Note 2)	IOPL	+4.0	А
	FAULT Output Current		IFAULT	8	mA
	FAULT Pin Voltage		V <sub>FAULT</sub>	-0.5 to V <sub>CC1</sub>	V
	Total Output Supply Voltage		(V <sub>CC2</sub> –V <sub>EE</sub> )	-0.5 to 35	V
	Negative Output Supply Voltage		$(V_E - V_{EE})$	-0.5 to 15	V
	Positive Output Supply Voltage		(V <sub>CC2</sub> –V <sub>E</sub> )	–0.5 to 35 – (V <sub>E</sub> –V <sub>EE</sub> )	V
	Output voltage		Vo	-0.5 to V <sub>CC2</sub>	V
	Peak Clamping Sinking Current		I <sub>Clamp</sub>	1.7	А
	Miller Clamping Pin Voltage		V <sub>Clamp</sub>	-0.5 to V <sub>CC2</sub>	V
	DESAT Voltage		V <sub>DESAT</sub>	$V_E$ to $V_E$ + 10	V
	Output power dissipation		Po	160	mW
	Output power dissipation (Ta ≥ 95°C	;)	Δ P <sub>O</sub> /ΔTa	-5.3	mW/°C
Common	Operating temperature range	Topr	-40 to 110	°C	
	Storage temperature range	Tstg	-55 to 125	°C	
	Lead soldering temperature (10 s)	Tsol	260	°C	
	Isolation voltage (AC, 60 s, R.H. ≤ 60	%) (Note 4)	BVs	5000	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- Note: A ceramic capacitor (1  $\mu$ F) should be connected from pin 13 to pin 9 to stabilize the operation of the high gain linear amplifier.Furthermore, in case V<sub>E</sub>-V<sub>EE</sub> > 0 V, a bypass capacitor, which has good high frequency characteristic, a ceramic capacitor (1  $\mu$ F) should be connected from pin 9 to pin 16. Failure to provide the bypassing may impair the switching property. The total lead length between capacitor and coupler should not exceed 1 cm.
- Note 1: Pulse width  $P_W \le 1 \ \mu s$ , 300 pps
- Note 2: Exponential waveform pulse width  $P_W \leq$  0.2  $\mu s,\,f \leq$  15 kHz,  $V_{CC}$  = 15 V
- Note 3: For the effective lead soldering area.
- Note 4: This device considered a two-terminal device: All pins on the LED side are shorted together, and all pin on the photodetector side are shorted together.

### **Recommended Operating Conditions (Note)**

Characteristics	Symbol	Min	Тур.	Max	Unit
Total Output Supply Voltage (Note 5)	$(V_{CC2} - V_{EE})$	15	-	30	V
Negative Output Supply Voltage	(V <sub>E</sub> -V <sub>EE</sub> )	0	-	15	V
Positive Output Supply Voltage	$(V_{CC2} - V_E)$	15	-	$30 - (V_{E} - V_{EE})$	V
Input On-State Current (Note 6)	I <sub>F(ON)</sub>	7.5	-	12	mA
Input On-State Voltage	V <sub>F(OFF)</sub>	0	-	0.8	V
Operating frequency (Note 7)	f	-	-	50	kHz

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Note 5: If the Vcc rise slope is sharp, an internal circuit might not operate with stability. Please design the Vcc rise slope under 3.0 V /  $\mu$ s.

Note 6: Input signal rise time (fall time)  $\leq$  0.5 µs.

Note 7: Exponential waveform.  $I_{OPH} \ge -4.0 \text{ A} (\le 90 \text{ ns}), I_{OPL} \le 4.0 \text{ A} (\le 90 \text{ ns}), Ta = 110^{\circ}\text{C}$ 

### Electrical Characteristics (Note) (Ta = -40 to 110 °C, unless otherwise specified)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.*	Max	Unit
Input Forward Voltage	V <sub>F</sub>	_	l⊧ = 10 mA, Ta = 25°C	1.4	-	1.7	V
Input Reverse Current	I <sub>R</sub>	_	V <sub>R</sub> = 5 V	-	-	10	μΑ
Input Capacitance	Ct	_	V=0 V, f=1 MHz, Ta = 25°C	-	95	-	pF
	V <del></del>		IFAULT = 1.1 mA, V <sub>CC</sub> 1=5.5 V	-	0.2	0.4	v
FAULT Low Level Output Voltage	VFAULTL	_	$I_{FAULT} = 1.1 \text{ mA}, V_{CC}1=3.3 \text{ V}$	-	0.2	0.4	v
			V <sub>FAULT</sub> = 5.5 V, V <sub>CC</sub> 1 = 5.5 V, Ta = 25°C	-	-	0.5	
FAULT High Level Output Current	IFAULTH	_	V <sub>FAULT</sub> = 5.5 V, V <sub>CC</sub> 1 = 3.3 V, Ta = 25°C	-	-	0.3	μA
Link Louis Output Current (Nata 0)		4	$V_0 = V_{CC}2 - 4 V$	-	-4.0	-1.2	
High Level Output Current (Note 8)	I <sub>OPH</sub>	1	$V_0 = V_{CC}2 - 7 V$	-	-6.5	-3.0	
Level Quite it Current (Mate 0)		0	$V_O = V_{EE} + 2.5 \text{ V}$	1.2	3.5	-	A
Low Level Output Current (Note 8)	I <sub>OPL</sub>	2	$V_O = V_{EE} + 7 \ V$	3	5.5	-	
Low Level Output Current					450		
During Fault Condition	I <sub>OLF</sub>	_	$V_O - V_{EE} = 14 V$	90	150	230	mA
High Level Output Voltage	V <sub>OH</sub>	3	I <sub>O</sub> = -100 mA	V <sub>CC</sub> 2-0.3	V <sub>CC</sub> 2-0.2	-	
Low Level Output Voltage	V <sub>OL</sub>	5	l <sub>o</sub> = 100 mA	-	0.1	0.2	V
Clamp Pin Threshold Voltage	V <sub>tClamp</sub>	_	—	-	3.0	-	
Clamp Low Level Sinking Current	I <sub>CL</sub>	_	$V_O = V_{EE} + 2.5 \ V$	0.56	1.8	-	А
High Level Supply Current	I <sub>CC2H</sub>	5	$I_0 = 0 \text{ mA}$	-	2.4	3.5	
Low Level Supply Current	I <sub>CC2L</sub>	6	$I_0 = 0 \text{ mA}$	-	2.3	3.5	
Blanking Capacitor Charging Current	I <sub>CHG</sub>	7	V <sub>DESAT</sub> = 2 V	-0.13	-0.24	-0.33	mA
Blanking Capacitor Discharge Current	I <sub>DSCHG</sub>	8	V <sub>DESAT</sub> = 7 V	10	49	-	
DESAT Threshold Voltage	V <sub>DESAT</sub>	_	V <sub>CC</sub> 2-V <sub>E</sub> >V <sub>UVLO-</sub>	6	6.5	7.5	
LIV/L O. Thursehold ) (alterna	$V_{\rm UVLO}^{+}$	9	V <sub>0</sub> >5 V	10.5	11.6	13.5	
UVLO Threshold Voltage	V <sub>UVLO</sub> -	10	$V_0 < 5 V$	9.2	10.3	11.1	V
UVLO hysteresis	UVLO <sub>HYS</sub>	_	_	-	1.3	-	1

(\*): All typical values are at  $Ta = 25^{\circ}C$ 

Note 8: I<sub>0</sub> application time  $\leq$  50 µs, 1 pulse

### Electrical Characteristics (Note) (Ta = -40 to 110 °C, unless otherwise specified)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Тур.*	Max	Unit
Threshold Input Current(L/H)	IFLH	10	$V_{CC} = 30 \text{ V}, \text{ V}_0 < 5 \text{ V}$	-	0.8	6	mA
Threshold Input Voltage (H/L)	VFHL	_	V <sub>CC</sub> = 30 V, V <sub>O</sub> > 5 V	0.8	-	-	V

(\*): All typical values are at  $Ta = 25^{\circ}C$ 

Note: This product is more sensitive than conventional products to electrostatic discharge (ESD) owing to its low power consumption design.

It is therefore all the more necessary to observe general precautions regarding ESD when handling this component.

### Isolation Characteristics (Note) (Ta = 25 °C)

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Capacitance input to output	Cs	Vs = 0 V, f = 1 MHz	-	1.0	-	pF
Isolation resistance	Rs	R.H. ≤ 60 %, Vs = 500 V	1×10 <sup>12</sup>	10 <sup>14</sup>	-	Ω
		AC, 60 s	5000	-	-	Marris
Isolation voltage	BVs	AC, 1 s, in oil	-	10000	-	Vrms
		DC, 60 s, in oil	-	10000	-	Vdc

Note: This device considered a two-terminal device: This device considered a two-terminal device: All pins on the LED side are shorted together, and all pin on the photodetector side are shorted together.

### Switching Characteristics (Note) (Ta = -40 to 110 °C, unless otherwise specified)

Characteristics		Symbol	Test Circuit	Test	Condition	Min	Typ.*	Max	Unit
Propagation delay time	$L\toH$	tpLH			$I_F=0 \rightarrow 10 \text{ mA}$	50	85	150	
(Note 9)	$H\toL$	tphl		V	$I_F = 10 \rightarrow 0 \text{ mA}$	50	90	150	
Output rise time (10-90 %	) (Note 9)	tr		$V_{CC2} = 30 V$ $R_g = 10 \Omega$	$I_F = 0 \rightarrow 10 \text{ mA}$	-	32	-	
Output fall time (90-10 %)	(Note 9)	tf	11	C <sub>g</sub> = 25 nF	$I_F = 10 \rightarrow 0 \text{ mA}$	-	18	-	ns
Pulse with distortion	(Note 9)	tpHL−tpLH		Duty = 50%	$I_F = 0 \leftrightarrow 10 \text{ mA}$	-	-	50	
Propagation delay skew (device to device)	(Note 9) (Note 10)	tpsk		$I_F = 0 \leftrightarrow 10 \text{ mA}$	-80	-	80		
DESAT Sense to 90% De	lay	t <sub>DESAT(90%)</sub>		$C_{\text{DESAT}}$ = 100 pF, Rg = 10 $\Omega$ Cg = 25 nF, V <sub>CC2</sub> = 30 V R <sub>F</sub> = 2.1 k $\Omega$		-	180	500	
DESAT Sense to 10% De	lay	t <sub>DESAT(10%)</sub>				-	3.5	5	μs
DESAT Sense to Low Lev FAULT Signal Delay	el	t <sub>DESAT(FAULT)</sub>	12	C <sub>DESAT</sub> = 100 p		-	300	500	20
DESAT Sense to Low Pro Delay	pagation	t <sub>DESAT(LOW)</sub>	12	Cg = 25 nF, Vα R <sub>F</sub> = 2.1 kΩ	CC2 = 30 V	-	200	-	ns
DESAT Input Mute		t <sub>DESAT(MUTE)</sub>		C <sub>F</sub> = Open		7	14	-	
RESET to High Level FAL Signal Delay	JLT	t <sub>reset(fault)</sub>			$V_{CC1} = 5.5 \ V$	0.2	0.45	2	μS
Common Mode Transient at High Level Output	Immunity	СМн	13		$\begin{array}{l} I_F = 10 \text{ mA} \\ V_O \text{ (min)} = 26 \text{ V} \end{array}$	±35	-	-	k)//uc
Common Mode Transient at Low Level Output	Immunity	CML	13	IF = 0 mA Vo (max) = 1 V		±35	-	-	kV/μs

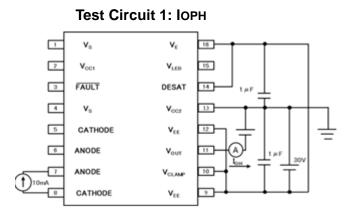
(\*): All typical values are at Ta = 25 °C.

Note 9: Input signal (f = 10 kHz, duty = 50%, tr = tf = 5 ns or less)

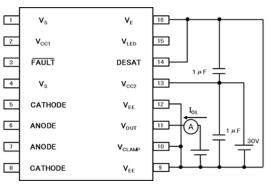
CL is approximately 15 pF which includes probe and stray wiring capacitance.

Note 10: The propagation delay skew, tpsk, is equal to the magnitude of the worst-case difference in tpHL and/or tpLH that will be seen between units at the same given conditions (supply voltage, input current, temperature, etc).

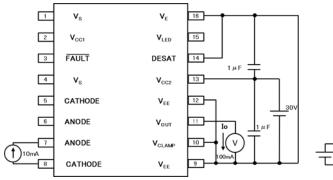
### Test Circuit



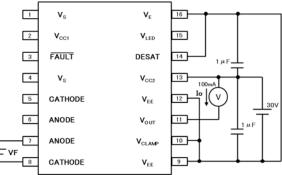
### Test Circuit 2: IOPL



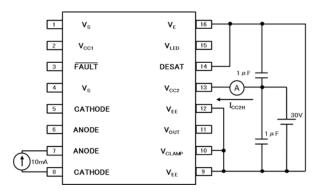
### Test Circuit 3: VOн



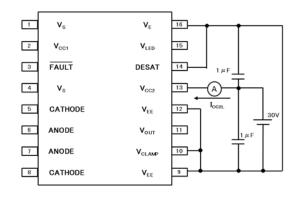
### Test Circuit 4: VoL



### Test Circuit 5: ICC2H

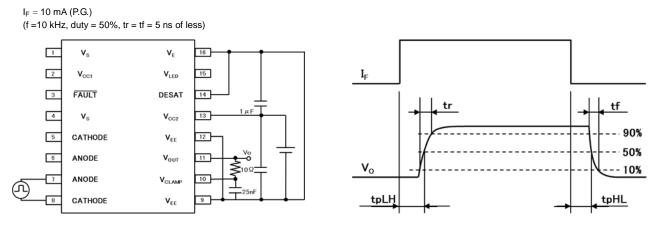


### Test Circuit 6: ICC2L

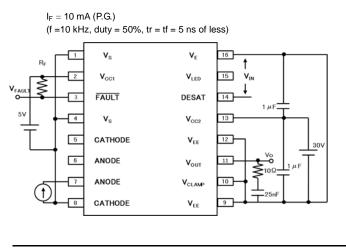


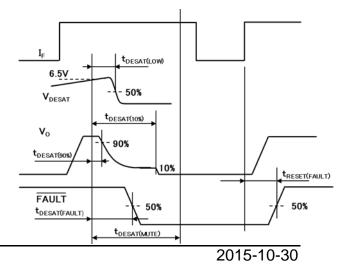
#### Test Circuit 7: ICHG **Test Circuit 8: IDSCHG** 1 ٧s 1 ٧c Vs $V_{\text{E}}$ 16 16 15 2 V<sub>CC1</sub> VLED 15 2 V<sub>CC1</sub> $V_{\text{LED}}$ FAULT A 3 FAULT 3 DESAT DESAT 14 A 14 1 # F 1μF . CHG 4 13 4 ٧s 13 vs $V_{\rm CC2}$ $V_{\rm CC2}$ 5 5 CATHODE 12 CATHODE $V_{EE}$ 12 $V_{EE}$ 30 30 6 11 11 6 ANODE Vout ANODE Vout $1 \mu F$ 10 10 ANODE 7 ANODE VCIAND 7 VCLAME 1)10mA CATHODE $V_{EE}$ 9 8 CATHODE $V_{\text{EE}}$ 9 **-**8 Test Circuit 9: VUVLO Test Circuit 10: IFLH 1 ٧s ٧<sub>E</sub> 16 1 Vs $\mathbf{V}_{\mathrm{E}}$ 16 2 V<sub>cc1</sub> $V_{LED}$ 15 2 V<sub>CC1</sub> $V_{\text{LED}}$ 15 3 FAULT 14 FAULT DESAT 3 1μF 1 # F DESAT 14 13 4 vs 4 $V_{\rm CC2}$ 13 $V_{\rm S}$ $V_{CC2}$ 5 CATHODE $V_{EE}$ 12 5 CATHODE 12 $V_{EE}$ **V**o •• v<sub>o</sub> 6 ANODE 11 6 11 VOUT ANODE Vout ANODE 10 ANODE 10 - 7 7 ᠿ 10mA $\widehat{}$ CATHODE CATHODE 8 $V_{EE}$ 9 8 $V_{EE}$ 9

### Test Circuit 11: tpLH, tpHL, tr, tf, | tpHL-tpLH |

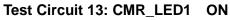


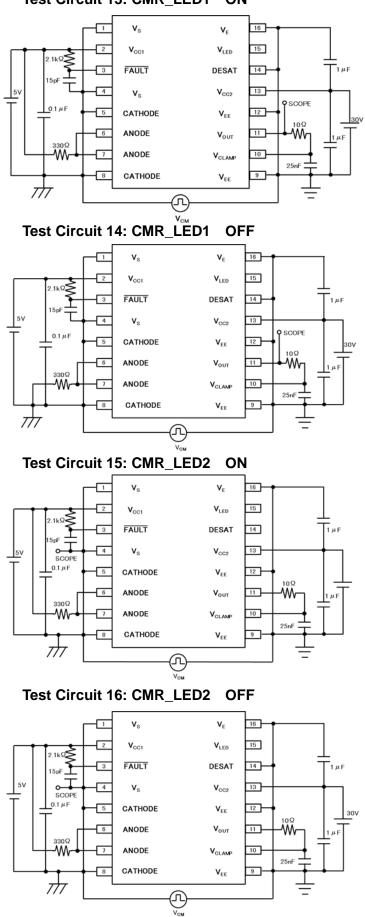
### Test Circuit 12: tdesat(90%), tdesat(10%), tdesat(fault), tdesat(Low), tdesat(mute), treset(fault)





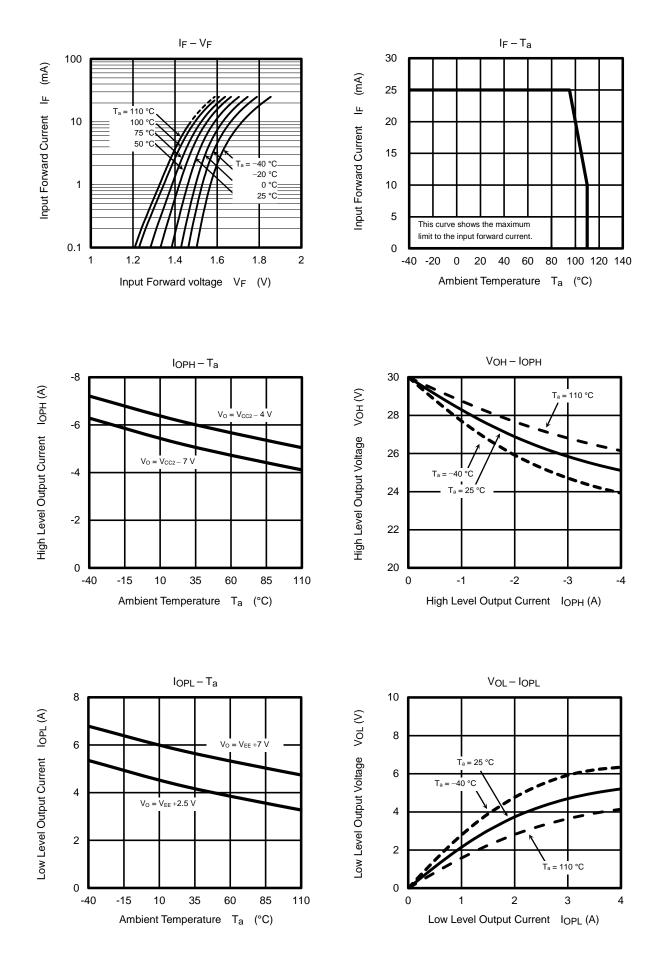


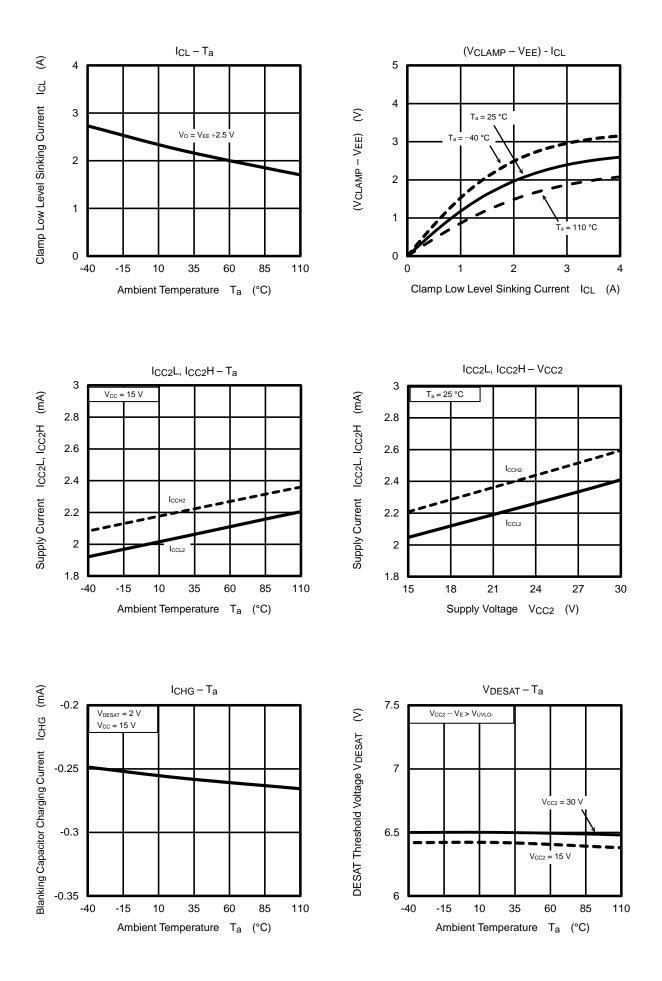


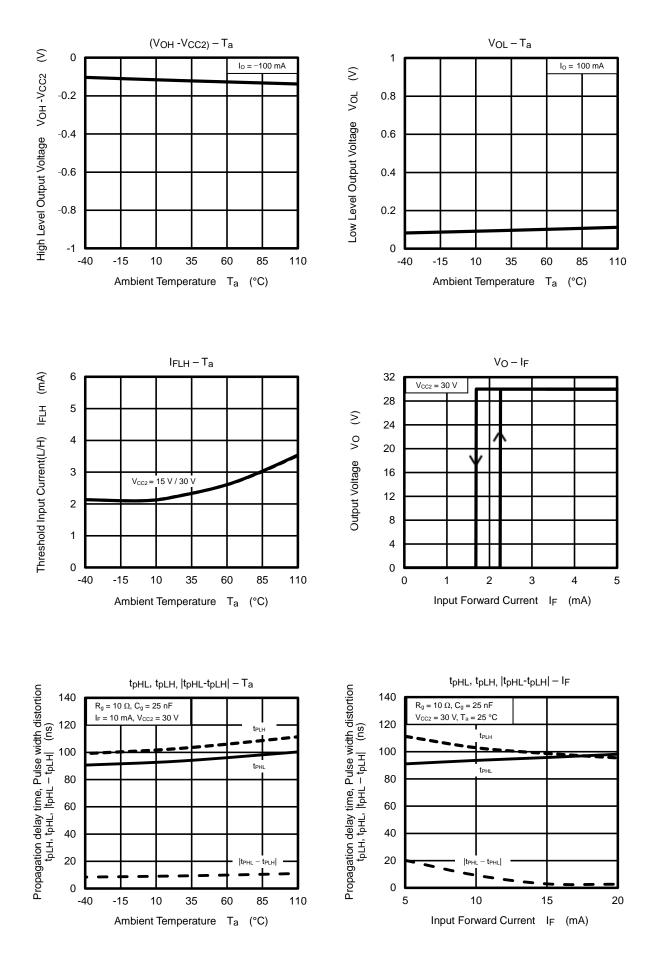


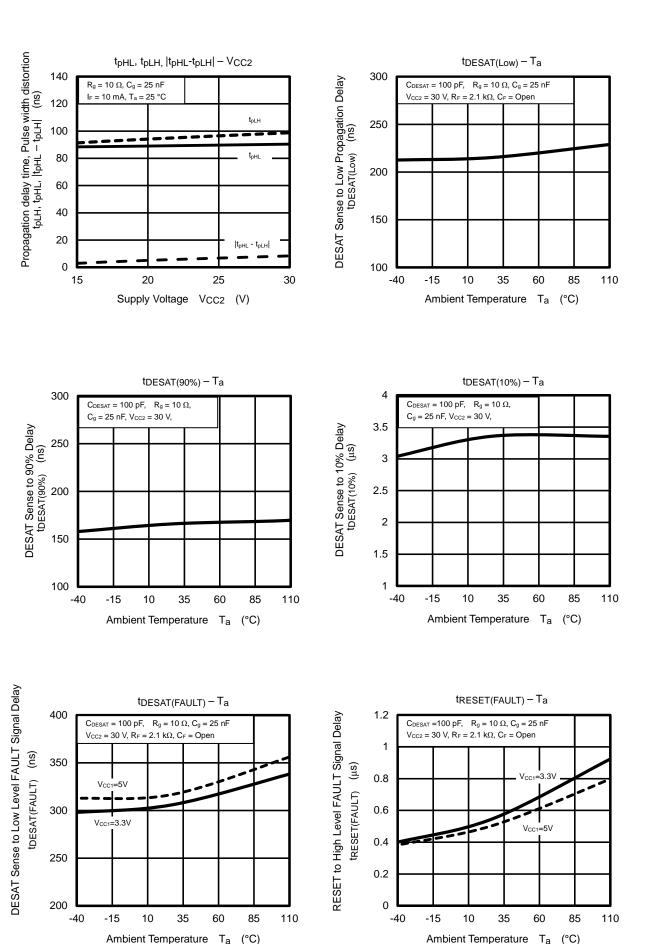
CM<sub>L</sub> (CM<sub>H</sub>) is the maximum rate of rise (fall) of the common mode voltage that can be sustained with the output voltage in the LOW (HIGH) state.

### **Characteristics Curve**









### PRECAUTIONS OF SURFACE MOUNTING TYPE PHOTOCOUPLER SOLDERING &

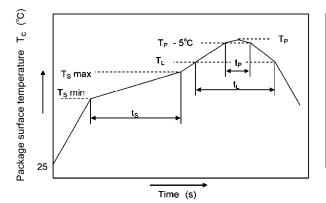
### GENERAL STORAGE

### (1) Precautions for Soldering

The soldering temperature should be controlled as closely as possible to the conditions shown below, irrespective of whether a soldering iron or a reflow soldering method is used.

1) When Using Soldering Reflow

An example of a temperature profile when lead(Pb)-free solder is use



	Symbol	Min	Max	Unit
Preheat temperature	Τs	150	200	°C
Preheat time	ts	60	120	s
Ramp-up rate $(T_L \text{ to } T_P)$			3	°C/s
Liquidus temperature	ΤL	2 <sup>.</sup>	17	°C
Time above T <sub>L</sub>	tL	60	150	S
Peak temperature	Τ <sub>Ρ</sub>		260	°C
Time during which $T_c$ is between ( $T_P - 5$ ) and $T_P$	t <sub>P</sub>		30	s
Ramp-down rate $(T_P \text{ to } T_L)$			6	°C/s

### An Example of a Temperature Profile When Lead(Pb)-Free Solder Is Used

- Reflow soldering must be performed once or twice.
- The mounting should be completed with the interval from the first to the last mountings being 2 weeks.

2) When using soldering Flow

- Apply preheating of 150 °C for 60 to 120 seconds.
- Mounting condition of 260 °C or less within 10 seconds is recommended.
- Flow soldering must be performed once

3) When using soldering Iron

• Complete soldering within 10 seconds for lead temperature not exceeding 260 °C or within 3 seconds not exceeding 350 °C.

• Heating by soldering iron must be only once per 1 lead

### (2) Precautions for General Storage

- 1) Do not store devices at any place where they will be exposed to moisture or direct sunlight.
- 2) When transportation or storage of devices, follow the cautions indicated on the carton box.
- 3) The storage area temperature should be kept within a temperature range of 5 degree C to 35 degree C, and relative humidity should be maintained at between 45% and 75%.
- 4) Do not store devices in the presence of harmful (especially corrosive)gases, or in dusty conditions.
- 5) Use storage areas where there is minimal temperature fluctuation. Because rapid temperature changes can cause condensation to occur on stored devices, resulting in lead oxidation or corrosion, as a result, the solderability of the leads will be degraded.
- 6) When repacking devices, use anti-static containers.
- 7) Do not apply any external force or load directly to devices while they are in storage.
- 8) If devices have been stored for more than two years, even though the above conditions have been followed, it is recommended that solderability of them should be tested before they are used.

### Specifications for Embossed-Tape Packing (TP) for SO16L Coupler

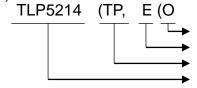
### 1. Applicable Package

Package	Product Type
SO16L	Long creepage Coupler

### 2. Product Naming System

Type of package used for shipment is denoted by a symbol suffix after a product number. The method of classification is as below.

(Example)



Domestic ID (Country / Region of origin: Japan) [[G]]/RoHS COMPATIBLE (Note) Tape type Device name

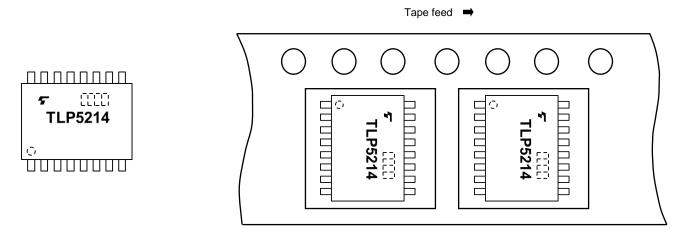
Note : Please contact your TOSHIBA sales representative for details as to environmental matters such as the RoHS compatibility of Product.

The RoHS is the Directive 2011/65/EU of the European Parliament and of the Council of 8 June 2011 on the restriction of the use of certain hazardous substances in electrical and electronics equipment.

### 3. Tape Dimensions

### 3.1 Orientation of Device in Relation to Direction of Tape Movement

Device orientation in the recesses is as shown in Figure 1.





3.2 Packing Quantity: 1500 per reel

3.3 Empty Device Recesses Are as Shown in Table 1.

Table1	Empty	Device	Recesses
--------	-------	--------	----------

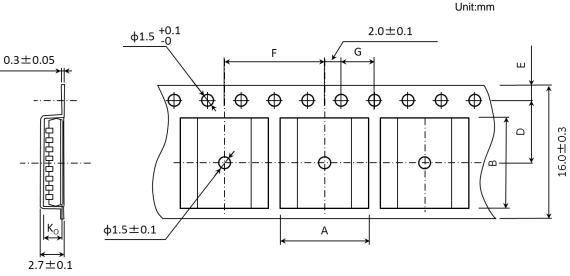
	Standard	Remarks	
Occurrences of 2 or more successive empty device recesses	0 device	Within any given 40-mm section of tape, not including leader and trailer	
Single empty device recesses	6 device (max) per reel	Not including leader and trailer	

#### 3.4 Start and End of Tape

The start of the tape has 14 or more empty holes. The end of the tape has 34 or more empty holes and more than 30mm only for a cover tape.

#### 3.5 Tape Specification

- (1) Material: Plastic (production against electrostatics)
- (2) Dimensions: The tape dimensions are shown in Figure 2 and Table 2.



#### Figure 2 Tape Forms

#### **Table 2 Tape Dimensions**

Unit: mm

		Unless otherwise specified: ±0.1
Symbol	Dimension	Remark
A	10.4	—
В	10.7	—
D	7.5	Center line of indented square hole and sprocket hole
E	1.75	Distance between tape edge and hole center
F	12.0	Cumulative error +0.1 (max) per 10 feed holes
G	4.0	Cumulative error $^{+0.1}_{-0.3}$ (max) per 10 feed holes
K <sub>0</sub>	2.4	Internal space

### 3.6 Reel

- (1) Material: Plastic
- (2) Dimensions: The reel dimensions are as shown in Figure 3 and Table 3.

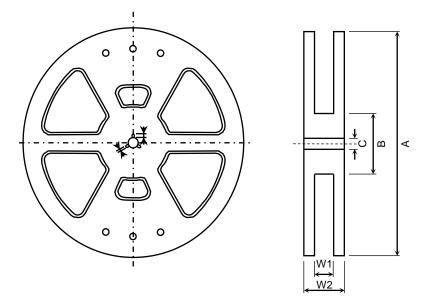


Table 4 R	eel Dimension
-----------	---------------

	Unit: mm
Symbol	Dimension
А	Φ330 ± 2
В	Φ100 ± 1
С	Φ13 ± 0.5
E	$2.0 \pm 0.5$
U	$4.0 \pm 0.5$
W1	17.4 ± 1.0
W2	21.4 ± 1.0

Figure 3 Reel Forms

### 4. Packing

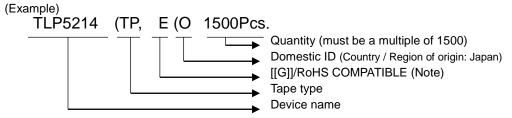
Either one reel or ten reels of photocoupler are packed in a shipping carton.

### 5. Label Indication

The carton bears a label indicating the product number, the symbol representing classification of standard, the quantity, the lot number and Toshiba company name.

### 6. Ordering Method

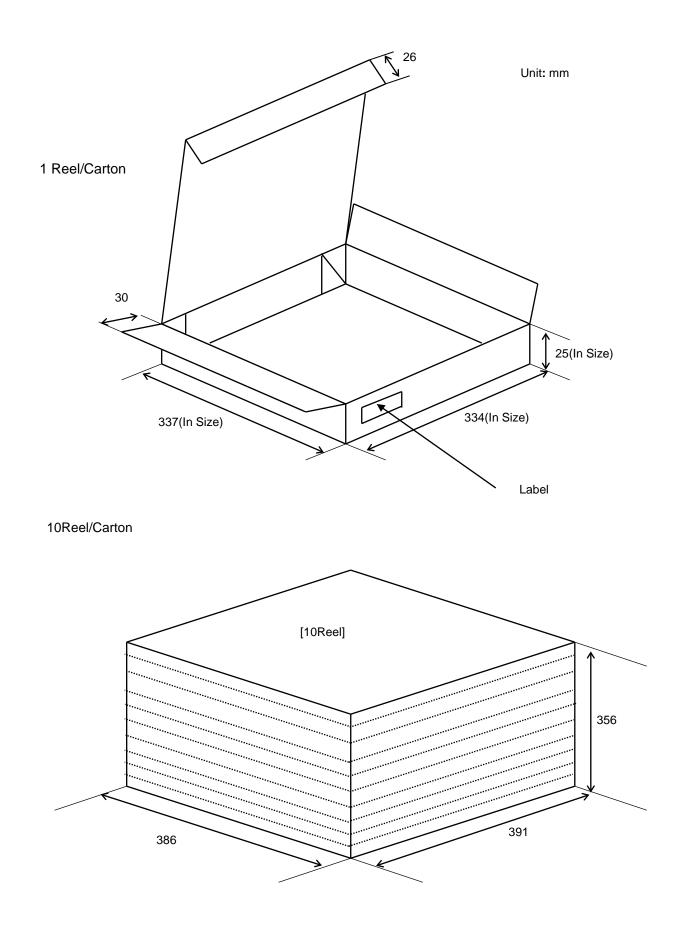
When placing an order, please specify the product number, the CTR rank, the tape and the quantity as shown in the following example.



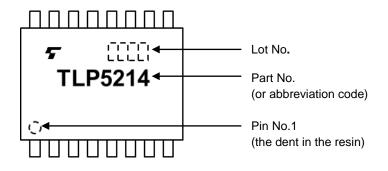
Note : Please contact your TOSHIBA sales representative for details as to environmental matters such as the RoHS compatibility of Product.

The RoHS is the Directive 2011/65/EU of the European Parliament and of the Council of 8 June 2011 on the restriction of the use of certain hazardous substances in electrical and electronics equipment.

### 7. Packing Dimensions ( $\phi$ 330 mm)



8. Marking



### **RESTRICTIONS ON PRODUCT USE**

- Toshiba Corporation, and its subsidiaries and affiliates (collectively "TOSHIBA"), reserve the right to make changes to the information in this document, and related hardware, software and systems (collectively "Product") without notice.
- This document and any information herein may not be reproduced without prior written permission from TOSHIBA. Even with TOSHIBA's written permission, reproduction is permissible only if reproduction is without alteration/omission.
- Though TOSHIBA works continually to improve Product's quality and reliability, Product can malfunction or fail. Customers are responsible for complying with safety standards and for providing adequate designs and safeguards for their hardware, software and systems which minimize risk and avoid situations in which a malfunction or failure of Product could cause loss of human life, bodily injury or damage to property, including data loss or corruption. Before customers use the Product, create designs including the Product, or incorporate the Product into their own applications, customers must also refer to and comply with (a) the latest versions of all relevant TOSHIBA information, including without limitation, this document, the specifications, the data sheets and application notes for Product and the precautions and conditions set forth in the "TOSHIBA Semiconductor Reliability Handbook" and (b) the instructions for the application with which the Product will be used with or for. Customers are solely responsible for all aspects of their own product design or applications; (b) evaluating and determining the applicability of any information contained in this document, or in charts, diagrams, programs, algorithms, sample application circuits, or any other referenced documents; and (c) validating all operating parameters for such designs and applications. TOSHIBA ASSUMES NO LIABILITY FOR CUSTOMERS' PRODUCT DESIGN OR APPLICATIONS.
- PRODUCT IS NEITHER INTENDED NOR WARRANTED FOR USE IN EQUIPMENTS OR SYSTEMS THAT REQUIRE EXTRAORDINARILY HIGH LEVELS OF QUALITY AND/OR RELIABILITY, AND/OR A MALFUNCTION OR FAILURE OF WHICH MAY CAUSE LOSS OF HUMAN LIFE, BODILY INJURY, SERIOUS PROPERTY DAMAGE AND/OR SERIOUS PUBLIC IMPACT ("UNINTENDED USE"). Except for specific applications as expressly stated in this document, Unintended Use includes, without limitation, equipment used in nuclear facilities, equipment used in the aerospace industry, medical equipment, equipment used for automobiles, trains, ships and other transportation, traffic signaling equipment, equipment used to control combustions or explosions, safety devices, elevators and escalators, devices related to electric power, and equipment used in finance-related fields. IF YOU USE PRODUCT FOR UNINTENDED USE, TOSHIBA ASSUMES NO LIABILITY FOR PRODUCT. For details, please contact your TOSHIBA sales representative.
- Do not disassemble, analyze, reverse-engineer, alter, modify, translate or copy Product, whether in whole or in part.
- Product shall not be used for or incorporated into any products or systems whose manufacture, use, or sale is prohibited under any applicable laws or regulations.
- The information contained herein is presented only as guidance for Product use. No responsibility is assumed by TOSHIBA for any infringement of patents or any other intellectual property rights of third parties that may result from the use of Product. No license to any intellectual property right is granted by this document, whether express or implied, by estoppel or otherwise.
- ABSENT A WRITTEN SIGNED AGREEMENT, EXCEPT AS PROVIDED IN THE RELEVANT TERMS AND CONDITIONS OF SALE FOR PRODUCT, AND TO THE MAXIMUM EXTENT ALLOWABLE BY LAW, TOSHIBA (1) ASSUMES NO LIABILITY WHATSOEVER, INCLUDING WITHOUT LIMITATION, INDIRECT, CONSEQUENTIAL, SPECIAL, OR INCIDENTAL DAMAGES OR LOSS, INCLUDING WITHOUT LIMITATION, LOSS OF PROFITS, LOSS OF OPPORTUNITIES, BUSINESS INTERRUPTION AND LOSS OF DATA, AND (2) DISCLAIMS ANY AND ALL EXPRESS OR IMPLIED WARRANTIES AND CONDITIONS RELATED TO SALE, USE OF PRODUCT, OR INFORMATION, INCLUDING WARRANTIES OR CONDITIONS OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, ACCURACY OF INFORMATION, OR NONINFRINGEMENT.
- GaAs (Gallium Arsenide) is used in Product. GaAs is harmful to humans if consumed or absorbed, whether in the form of dust or vapor. Handle with care and do not break, cut, crush, grind, dissolve chemically or otherwise expose GaAs in Product.
- Do not use or otherwise make available Product or related software or technology for any military purposes, including without
  limitation, for the design, development, use, stockpiling or manufacturing of nuclear, chemical, or biological weapons or missile
  technology products (mass destruction weapons). Product and related software and technology may be controlled under the
  applicable export laws and regulations including, without limitation, the Japanese Foreign Exchange and Foreign Trade Law and the
  U.S. Export Administration Regulations. Export and re-export of Product or related software or technology are strictly prohibited
  except in compliance with all applicable export laws and regulations.
- Please contact your TOSHIBA sales representative for details as to environmental matters such as the RoHS compatibility of Product. Please use Product in compliance with all applicable laws and regulations that regulate the inclusion or use of controlled substances, including without limitation, the EU RoHS Directive. **TOSHIBA ASSUMES NO LIABILITY FOR DAMAGES OR LOSSES OCCURRING AS A RESULT OF NONCOMPLIANCE WITH APPLICABLE LAWS AND REGULATIONS.**

### **X-ON Electronics**

Largest Supplier of Electrical and Electronic Components

Click to view similar products for IGBT Modules category:

Click to view products by Toshiba manufacturer:

Other Similar products are found below :

 F3L100R07W2E3\_B11
 F3L15R12W2H3\_B27
 F3L400R07ME4\_B22
 F3L400R12PT4\_B26
 F4-100R12KS4
 F4-50R07W2H3\_B51
 F4 

 75R12KS4\_B11
 FB15R06W1E3
 FB20R06W1E3\_B11
 FD1000R33HE3-K
 FD300R06KE3
 FD300R12KE3
 FD300R12KS4\_B5

 FD400R12KE3
 FD400R33KF2C-K
 FD401R17KF6C\_B2
 FD-DF80R12W1H3\_B52
 FF100R12KS4
 FF1200R17KE3\_B2
 FF150R12KE3G

 FF200R06KE3
 FF200R06YE3
 FF200R12KT3
 FF200R12KT3\_E
 FF200R12KT4
 FF200R17KE3
 FF300R12KE4\_E

 FF300R12KS4HOSA1
 FF300R12ME4\_B11
 FF300R12MS4
 FF300R17ME4
 FF450R12ME4P
 FF450R17IE4
 FF600R12IE4V

 FF600R12IP4V
 FF800R17KP4\_B2
 FF900R12IE4V
 MIXA30W1200TED
 MIXA450PF1200TSF
 FP06R12W1T4\_B3
 FP100R07N3E4

 FP100R07N3E4\_B11
 FP10R12W1T4\_B11
 FP10R12YT3
 FP10R12YT3\_B4
 FP15R12KT3

 FP15R12W2T4
 F
 FF15R12W2T4
 FF15R12W2T4
 FF15R12W2T4